

<b>Notice of References Cited</b>	Application/Control No. 10/734,198		Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Adeel Haroon		Art Unit 2618	Page 1 of 1

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*	C	US-6,243,563	06-2001	Nakamura, Taisuke	455/78
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